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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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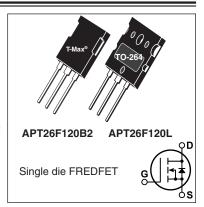


APT26F120B2 APT26F120L

1200V, 27A, 0.58Ω Max, $t_{rr} \le 335ns$

N-Channel FREDFET

Power MOS 8^{TM} is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced t_{rr} , soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of $C_{\text{rss}}/C_{\text{iss}}$ result in excellent noise immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



FEATURES

- · Fast switching with low EMI
- · Low trr for high reliability
- Ultra low C_{rss} for improved noise immunity
- · Low gate charge
- · Avalanche energy rated
- RoHS compliant

TYPICAL APPLICATIONS

- ZVS phase shifted and other full bridge
- Half bridge
- PFC and other boost converter
- Buck converter
- · Single and two switch forward
- Flyback

Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
I_	Continuous Drain Current @ T _C = 25°C	27	
'D	Continuous Drain Current @ T _C = 100°C	16	Α
I _{DM}	Pulsed Drain Current ^①	105	
V _{GS}	Gate-Source Voltage	±30	V
E _{AS}	Single Pulse Avalanche Energy®	2165	mJ
I _{AR}	Avalanche Current, Repetitive or Non-Repetitive	14	Α

Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Тур	Max	Unit	
P _D	Total Power Dissipation @ T _C = 25°C			1135	W	
$R_{\theta JC}$	Junction to Case Thermal Resistance			0.11	°C/W	
$R_{\theta CS}$	Case to Sink Thermal Resistance, Flat, Greased Surface		0.11			
T _J ,T _{STG}	Operating and Storage Junction Temperature Range	-55		150	°C	
T _L	Soldering Temperature for 10 Seconds (1.6mm from case)			300		
W _T	Package Weight		0.22		OZ	
			6.2		g	
Torque	Mounting Torque (TO-264 Package), 4-40 or M3 screw			10	in∙lbf	
				1.1	N⋅m	

Static Characteristics

T_J = 25°C unless otherwise specified

AP1	26F	120	B2	L

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V _{BR(DSS)}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_{D} = 250\mu A$	1200			V
$\Delta V_{BR(DSS)}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I _D = 250µA	١	1.41		V/°C
R _{DS(on)}	Drain-Source On Resistance [®]	$V_{GS} = 10V, I_{D} = 14A$		0.48	0.58	Ω
V _{GS(th)}	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 2.5 \text{mA}$	2.5	4	5	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Threshold Voltage Temperature Coefficient			-10		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 1200V$ $T_{J} = 25^{\circ}C$			250	μΑ
		$V_{GS} = 0V$ $T_J = 125^{\circ}C$			1000	μΛ
I _{GSS}	Gate-Source Leakage Current	V _{GS} = ±30V			±100	nA

Dynamic Characteristics

T₁ = 25°C unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
9 _{fs}	Forward Transconductance	$V_{DS} = 50V, I_{D} = 14A$		31		S
C _{iss}	Input Capacitance	V 0V V 05V		9670		
C _{rss}	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ f = 1MHz		115		
C _{oss}	Output Capacitance			715		pF
$C_{o(cr)} \textcircled{4}$	Effective Output Capacitance, Charge Related	$V_{GS} = 0V, \ V_{DS} = 0V \text{ to } 800V$		275		
C _{o(er)} ⑤	Effective Output Capacitance, Energy Related			140		
Q _g	Total Gate Charge	V 01 10V 1 11A		300		
Q_{gs}	Gate-Source Charge	$V_{GS} = 0 \text{ to } 10V, I_{D} = 14A,$ $V_{DS} = 600V$		50		nC
Q_{gd}	Gate-Drain Charge	v _{DS} = 600V		140		
t _{d(on)}	Turn-On Delay Time	Resistive Switching		50		
t _r	Current Rise Time	V _{DD} = 800V, I _D = 14A		31		nc
t _{d(off)}	Turn-Off Delay Time	$R_{G} = 2.2\Omega^{\textcircled{6}}, V_{GG} = 15V$		170		ns
t _f	Current Fall Time			48		

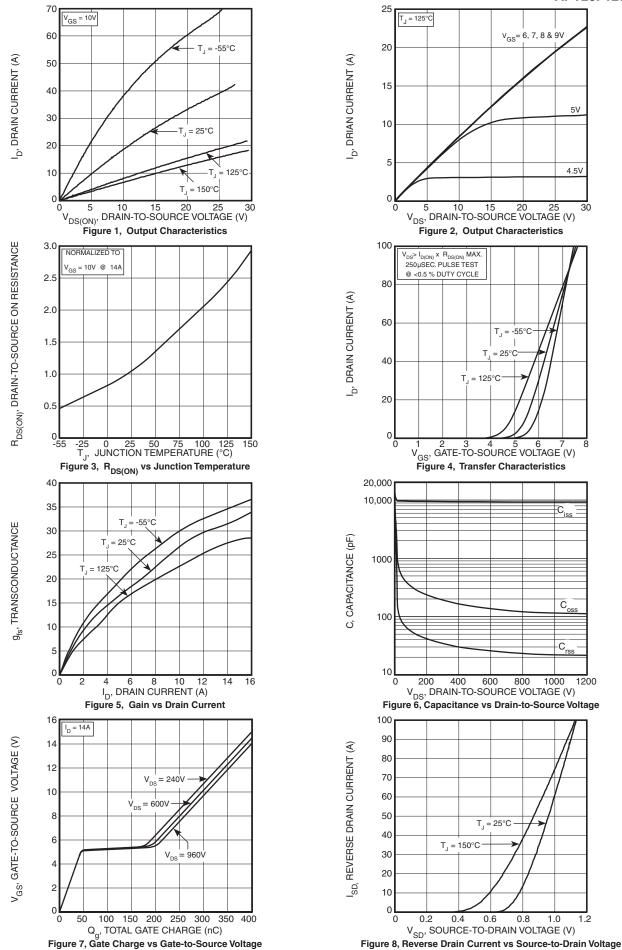
Source-Drain Diode Characteristics

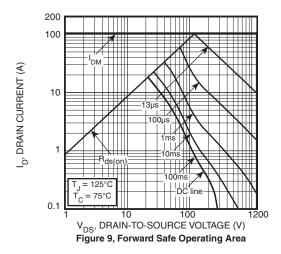
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
I _s	Continuous Source Current (Body Diode)	showing the	D .		27	A
I _{SM}	Pulsed Source Current (Body Diode) ^①	integral reverse p-n junction diode (body diode)	s		105	^
V _{SD}	Diode Forward Voltage	$I_{SD} = 14A, T_{J} = 25^{\circ}C, V_{GS} = 0V$			1.2	V
t _{rr}	Deverse Bessyant Time	T _J = 25°C			335	no
rr	Reverse Recovery Time	T _J = 125°C			640	ns
Q _{rr}	Reverse Recovery Charge	$I_{SD} = 14A^{\textcircled{3}}$ $T_{J} = 25^{\circ}C$		1.72		
rr		$V_{DD} = 100V$ $T_{J} = 125^{\circ}C$		4.67		μC
1	Reverse Recovery Current	$di_{SD}/dt = 100A/\mu s$ $T_J = 25^{\circ}C$		11		Α
'rrm		T _J = 125°C		16] ^
dv/dt	Peak Recovery dv/dt	$I_{SD} \le 14A$, di/dt $\le 1000A/\mu s$, $V_{DD} = 800V$, $T_{J} = 125^{\circ}C$			25	V/ns

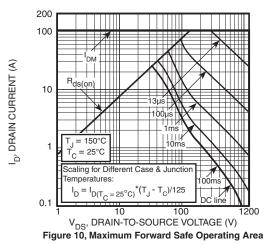
- 1 Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- ② Starting at $T_J = 25^{\circ}C$, L = 22.09mH, $R_G = 25\Omega$, $I_{AS} = 14$ A.
- (3) Pulse test: Pulse Width < 380µs, duty cycle < 2%.

- 6 R_G is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

Microsemi reserves the right to change, without notice, the specifications and information contained herein.







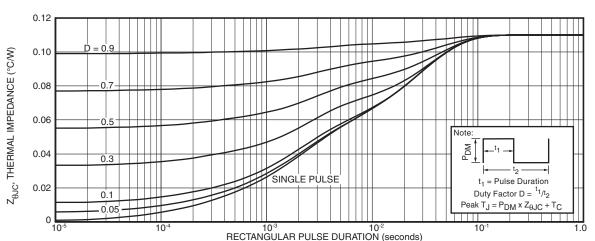


Figure 11. Maximum Effective Transient Thermal Impedance Junction-to-Case vs Pulse Duration

T-MAX® (B2) Package Outline

TO-264 (L) Package Outline

